

Europe PV Materials Committee Meeting Summary and Minutes

Intersolar Europe
11 June 2015, 10am – 12pm (CET)
ICM, Munich, Germany

Next Committee Meeting

SEMICON Europa 2015
October 6-8, 2015
Dresden, Germany

Table 1 Meeting Attendees

Co-Chairs: Peter Wagner (consultant)

SEMI Staff: Stephan Raithel (SEMI Europe)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
Jacobs University Brennen	Bergholz	Werner	Fraunhofer CSP	Hagendorf	Christian
Wacker	Dornberger	Erich	Semilab	Jahrling	Thomas
Freiburg Instruments	Dornich	Viay	Solarworld	Kleiss	Gerhard
CoLa	Fabry	Laszlo	Solarworld	Miller	Armin
Hanwha Q-Cells	Gottermann	Thomas	Consultant	Wagner	Peter

Excused: Hubert Aulich

Table 2 Ballot Results

None

Table 3 Authorized Ballots (or move to Section New Business)

None

Table 4 Authorized Activities (or move to Section Action Item Review)

#	Type	SC/TF/WG	Details
N/A	TFOF	N/A	PV Material Degradation Task Force
5889	SNARF	PV Material Degradation Task Force	New Standard: Test Method on cell level for potential-induced degradation susceptibility of solar cells and module encapsulation materials

Table 5 Previous Meeting Actions Items (or move to Section 8, Action item Review)

Item #	Assigned to	Details
1009-01	Yann Guillou	Clarify #5382 and PV22. Shall 5382 be included in PV22? DONE
1009-02	Yann Guillou	Inform China about IEC 61646 that may have a very similar scope than #5478 OPEN
1009-03	Yann Guillou	Check sponsor of SNARF #5429 OPEN
1009-04	Yann Guillou	Check status of #4833 OPEN
1009-05	Yann Guillou	Send a mail to Jason Lin to inform Taiwan committee there is an on-going activity on Wafer Measurement Methods DONE

Table 6 Future action items (or move to Section 8, Action item Review)

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
1506-01	SEMI	Give info on doc #5567 to Erich Dornberger

1 Welcome, Reminders, and Introductions

Peter Wagner called the meeting to order at 10am. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

2 Liaison Reports

2.1 *China PV Committee*

Stephan Raithel reported for the China PV Committee.

Attachment: 1

2.2 *Japan PV/ PV Materials Committee*

Stephan Raithel reported for the Japan PV/PV Materials Committee.

Attachment: 2

2.3 *NA PV Committee*

Stephan Raithel reported for the NA PV Committee.

Attachment: 3

2.4 *SEMI Staff Report*

Stephan Raithel gave the SEMI Staff Report.

Attachment: 4

3 Old Business

3.1 Erich Dornberger requested to see the document 5567

3.2 Erich Dornberger questioned the publication of PV 50-0114 after he objected to its publication at a PV Standards meeting in China.

4 Subcommittee & Task Force Reports

4.1 Silicon Materials TF

Peter Wagner reported for the Silicon Materials Task Force.

5 Authorized Activities

5.1 TFOF

PV Material Degradation Task Force

Motion: To approve SNARF
By / 2nd: Hagendorf / Bergholz
Discussion: None
Vote: 7/0 - Passed

Attachment: 6, TFOF: *PV Material Degradation Task Force*

5.2 SNARF

New Standard: Test Method on cell level for potential-induced degradation susceptibility of solar cells and module encapsulation materials

Motion: To approve SNARF, pending reception of LOI from Freiberg Instruments
By / 2nd: Hagendorf / Bergholz
Discussion: None
Vote: 7/0 – Passed (1 abstention)

5.2.1 Discussion:

- 1) An LOI is needed for this SNARF before any ballot is submitted. It is currently pending
- 2) Differentiation to existing PID testing processes / PID testing standards (e.g. IEC) should be clearly explained.

Attachment: 7, SNARF: *New Standard: Test Method on cell level for potential-induced degradation susceptibility of solar cells and module encapsulation materials*

6 Action Item Review

6.1 Open Action Items

Peter Wagner (Consultant) reviewed the open action items.

- 1009-01: Clarify #5382 and PV22. Shall 5382 be included in PV22?
 - o Closed
- 1009-02: Inform China about IEC 61646 that may have a very similar scope than #5478
 - o Still open
- 1009-03: Check sponsor of SNARF #5429
 - o Still open
- 1009-04: Check status of #4833
 - o #4833 reference is not correct – still open
- 1009-05: Send a mail to Jason Lin to inform Taiwan committee there is an on-going activity on Wafer Measurement Methods

- o Closed

These action items can be found in the Open Action Items table at the beginning of these minutes.

6.2 New Action Items

Peter Wagner (Consultant) reviewed the new action items:

- 1506: Respond to Erich Dornberger about doc 5567

These can be found in the New Action Items table at the beginning of these minutes.

7 Next Meeting and Adjournment

The next meeting of the EU PV Materials committee is scheduled for October 6-8, 2015 at SEMICON Europa in Dresden. Co-chairs adjourned the meeting at 12pm.

Respectfully submitted by:

Andrea Busch

SEMI Europe

Phone: +33 4 56 59 30 59

Email: abusch@semi.org

Minutes approved by:

Peter Wagner (self), Co-chair	July 10, 2015
-------------------------------	---------------

#	Title
1	China LR
2	Japan LR
3	NA LR
4	Staff Report
5	TFOF: <i>PV Material Degradation Task Force</i>
6	SNARF: <i>New Standard: Test Method on cell level for potential-induced degradation susceptibility of solar cells and module encapsulation materials</i>

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Andrea Busch at the contact information above.